

Notice of References Cited	Application/Control No. 10/626,765		Applicant(s)/Patent Under Reexamination CHIKU ET AL.	
	Examiner Nhan T. Tran		Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0117505	06-2003	Sasaki et al.	348/231.99
*	B	US-2005/0151858	07-2005	Nozaki et al.	348/231.9
*	C	US-6,674,467	01-2004	Lee, Sang-Gi	348/333.11
*	D	US-5,864,726	01-1999	Yamamoto, Yasuhiro	396/303
*	E	US-6,903,778	06-2005	Kaku, Junya	348/333.13
*	F	US-6,292,218	09-2001	Parulski et al.	348/333.11
*	G	US-6,351,287	02-2002	Sakaegi et al.	348/372
*	H	US-6,434,337	08-2002	Misawa, Takeshi	348/372
*	I	US-5,189,524	02-1993	Yoshida et al.	386/119
*	J	US-6,798,975	09-2004	Fukushima, Nobuo	386/125
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05-292444 (English)	11-1993	JAPAN	KUROKAWA HIROMITSU	H04N 5/782
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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